

# TEST PRODUCT QUALIFICATION REPORT

**TITLE:**

ADuM1200W/ADuM1201W SOIC\_N Test Platform  
Migration from CTS5040 to Teradyne MicroFlex

**PCN NUMBER:**

17\_0146

**REVISION:**

A

**DATE:**

August 14, 2017

## SUMMARY

The ADuM1200W/ADuM1201W are dual-channel digital isolators based on Analog Devices, Inc., *iCoupler*® technology. Combining high-speed CMOS and monolithic air core transformer technology, these isolation components provide outstanding performance characteristics superior to alternatives such as optocoupler devices. This product is being tested on the CTS5040 which is a constrained ADI manufactured tester. The proposed change is to add a new test capability on MicroFlex which is being manufactured by Teradyne.

There is no change to the form, fit, function, quality or reliability of the transferred parts.

This report documents the result of the evaluations done to qualify the Teradyne MicroFlex as a new platform for testing the ADuM1200W/ADuM1201W.

## TEST AND PRODUCT INFORMATION

Devices(Generics):	ADuM1200W	ADuM1201W
Package:	SOIC_N	SOIC_N
Leads:	8	8
Parts Affected:	ADUM1200WSRZ ADUM1200WSRZ-RL7 ADUM1200WTRZ ADUM1200WTRZ-RL7 ADUM1200WTRZ55 ADUM1200WTRZ55-RL7 ADUM1200WURZ ADUM1200WURZ-RL7	ADUM1201WSRZ ADUM1201WSRZ-RL7 ADUM1201WTRZ35 ADUM1201WTRZ35-RL7 ADUM1201WTRZ53 ADUM1201WTRZ53-RL7 ADUM1201WSRZ55 ADUM1201WSRZ55-RL7 ADUM1201WTRZ55 ADUM1201WTRZ55-RL7 ADUM1201WURZ ADUM1201WURZ-RL7
Current Platform:	CTS5040 with MT9308_PB_RN handler	CTS5040 with MT9308_PB_RN handler
New Platform:	MicroFlex with MT9308_PB_RN handler	MicroFlex with MT9308_PB_RN handler

**Description and Test Results** (Taken from the Test Platform Migration Criteria)

Table 1 & Table 2 provide a description of the qualification tests conducted and corresponding test results for ADuM1200W/ADuM1201W. All the units have undergone electrical tests on both the CTS5040 and Teradyne MicroFlex test platforms. Any device that did not meet the electrical qualification requirements, without further analysis and data to prove passing the qualification would be considered failed.

Table 1: Test Product Correlation Criteria

Generic	Package	Testing Site	CTS5040 Test Lot Size	MicroFlex Test Lot Size	% Mean Shift Criteria =< 5
ADuM1200W	SOIC_N	ADGT	100	100	Reviewed and Passed
ADuM1201W	SOIC_N	ADGT	100	100	Reviewed and Passed

Table 2: Test Product Guard banding (GB) Criteria

Generic	Package	Testing Site	CTS5040 Test Lot Size	MicroFlex Test Lot Size	Sigma Spread Criteria =< 1.3
ADuM1200W	SOIC_N	ADGT	100	100	Reviewed and Passed
ADuM1201W	SOIC_N	ADGT	100	100	Reviewed and Passed

Table 3: Shows results of the qualification lot run for the ADuM1200W/ADuM1201W. The qualification lot has undergone electrical test on both CTS5040 and Teradyne MicroFlex test platforms. Any deviation on the lot qualification run criteria without further analysis and data to prove a passing qualification would be considered a failed qualification lot run.

Table 3: Test Product Qualification Lot Run

Generic	Package	Lot number	Lot Size	Good units passed on both test platforms?	Reject units failed on the same test parameter for both test platforms?
ADuM1200WS	SOIC_N	AN24092.1	100	Yes	Yes
ADuM1200WU	SOIC_N	AN24094.1	100	Yes	Yes
ADuM1200WT	SOIC_N	AN24093.1	100	Yes	Yes
ADuM1201WS	SOIC_N	AO31417.1	100	Yes	Yes
ADuM1201WT	SOIC_N	AN24096.1	100	Yes	Yes
ADuM1201WU	SOIC_N	AO31418.1	100	Yes	Yes

### Approvals

Product Line Manager  
 Test Development Manager  
 Test Product Manager  
 Quality Manager

### Supporting Document

Technical Review Board: TRB# 42829

### Additional Information

ADI Homepage:

<http://www.analog.com/en/index.html>

ADI Datasheets:

[http://www.analog.com/media/en/technical-documentation/data-sheets/ADuM1200\\_1201.pdf](http://www.analog.com/media/en/technical-documentation/data-sheets/ADuM1200_1201.pdf)